

<b>Notice of References Cited</b>	Application/Control No. 10/581,633		Applicant(s)/Patent Under Reexamination SHIMA ET AL.	
	Examiner ANNA L. VERDERAME		Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,390,547	06-2008	Kim et al.	428/64.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	T. Shima and J. Tominaga. Japanese Journal of Applied Physics. 42(2003) 3479
	V	K.L. Saenger, C. Cabral, Jr., C. Lavoie, and S.M. Rossnagel. J. of Applied Physics. 86, 6084(1999)
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.